VOLUME CONTENTS

VOLUME 32, NUMBER 1/2 JAN/FEB 1992 PAGES 1–302

S. G. Chowdhury and K. B. Misra	1	Evaluation of fuzzy reliability of a non-series parallel network
M. N. Gopalan and S. S. Waghmare	5	Cost–benefit analysis of single server *n*-unit imperfect switch system with delayed repair
M. N. Gopalan and N. Anantharaman	11	Stochastic modelling of a two-stage transfer-line production system with end buffer and random demand
D. K. Pandey, S. M. Gupta and N. K. Jaiswal	17	Reliability analysis of two-unit warm standby system with partial failure mode and inspection time
M. Scherge, V. Breternitz and Ch. Knedlik	21	Simulation of electromigration behaviour in Al metallization of integrated circuits
Den-Jyi Chen and Ming-Cheng Sheng	25	A new recursive algorithm for the reliability evaluation of a distributed program
W. G. Schneeweiss	35	Fault-trees for a voting circuit; synthesis and joint analysis
V. Nicola, A. Bobbio and K. Trivedi	49	A unified performance reliability analysis of a system with a cumulative down time constraint
A. Noore, S. K. Tewksbury and M. Divakurani	67	On optimizing yield reliability and area overhead in large memory arrays
M. M. El-Fahham	79	A note on recursive estimator of the density function which is not necessarily continuous
B. N. Masters, T. O. Lewis and W. J. Kolarik	89	A confidence interval for the availability ratio for systems with Weibull operating time and lognormal repair time
E. Petrova and N. Malevris	101	Rules and criteria for when to stop testing a piece of software
Hoang Pham	119	Optimal design of *k*-out-of-*n* redundant systems
Who Kee Chung	127	Reliability analysis of a human operator under different levels of stress
V. N. Rayapati and D. Mukedkhar	133	Ultra high reliable spacecraft computer system design considerations
S. Yanagi	143	An approximation analysis for the availability of a parallel redundant system with general distributions
T. I. Sultan	159	Optimum reliability investment in the electronics industry
A. Scorzoni, G. L. Baldini and C. Caprile	167	Ohmic contact electromigration
W. J. Mee and G. S. Hura	175	Synchronization techniques for distributed systems: an overview
L. Anneberg, G. Rajappan, H. Singh and E. Yaprak	199	Parallel Petri net path searching on a local area network—object oriented Pascal implementation
D. K. Dey and Pei-San Liao Liu	207	On comparison of estimators in a generalized life model
A. H. Rawicz	223	Can a noninvasive reliability prediction of electronic boards be accurate?
A. S. Papadopoulos and R. C. Tiwari	233	Comparison of Bayesian nonparametric estimates of the reliability with rival estimates
S. K. Bhattacharya and R. C. Tiwari	241	Hierarchical Bayesian reliability analysis using Erlang families of priors and hyperpriors

R. Badarinathi and R. C. Tiwari — 249 Hierarchical Bayesian approach to reliability estimation under competing risk

A. Kyriakoussis and A. S. Papadopoulos — 259 The zero-truncated negative binomial distribution as a failure model from the Bayesian approach

Technical Notes

K. K. Govil — 265 Optimal maintainability allocation using the geometric programming method

K. K. Govil — 267 Fitting maintenance cost vs maintainability data to a standard curve

K. K. Govil — 269 A simple model for life cycle cost vs maintainability function

Xianhua Wei — 271 Testing whether one distribution is more IFR than another

275 Book Review
Fundamentals of Manipulator Calibration

277 Calendar of International Conferences, Symposia, Lectures and Meetings of Interest

281 Publications, Notices, Calls for Papers, etc.

283 World Abstracts on Microelectronics and Reliability

VOLUME 32, NUMBER 3 MAR 1992 PAGES 303–452

K. P. Soman and K. B. Misra — 303 A least square estimation of three parameters of a Weibull distribution

R. P. Anjard Sr — 307 Software quality assurance considerations

L. R. Goel and P. Shrivastava — 313 A single unit man–machine system with varying physical conditions of the repairman

S. K. Singh and G. C. Sharma — 319 Analysis of a composite performance reliability evaluation for Markovian queueing systems

Lee Gang Soo and Yoon Jung-Mo — 323 An empirical study on the complexity metrics of Petri nets

Hong-Zhou Wang, Bao-Hua Ma and Ju-Sheng Shi — 331 A research study of environmental factors for the gamma distribution

I. J. Jóźwiak — 337 Reliability exploration of microcomputer systems using the Weibull distribution

I. J. Jóźwiak — 341 Use of concomitant variables for reliability exploration of microcomputer systems

I. J. Jóźwiak — 345 The reliability and functional model of a computer network with a branched structure

R. K. Tuteja and S. C. Malik — 351 Reliability and profit analysis of two single-unit models with three modes and different repair policies of repairmen who appear and disappear randomly

J. P. Bhutani and A. Kumar — 357 M/G/I queue with rest period

R. Radojcic and P. Giotta — 361 Semiconductor device reliability vs process quality

M. W. Hughes, E. Y. DeSoto and Y. S. Sherif — 369 On software standards

Y. S. Sherif — 407 Software safety analysis: the characteristics of efficient technical walkthroughs

Y. S. Sherif — 415 The characteristics of efficient software formal reviews

Y. S. Sherif and J. C. Kelly	423	Improving software quality through formal inspections
Hoang Pham and D. W. Twigg	433	A note on the Venn and Ben diagrams
Tongde Guo and Jinhua Cao	439	Reliability analysis of a multistate one-unit repairable system operating under a changing environment
	445	Society of Reliability Engineers Bulletin
	447	Book Review *Application Specific Integrated Circuit (ASIC) Technology*
	449	Publications, Notices, Calls for Papers, etc.

VOLUME 32, NUMBER 4 APR 1992 PAGES 453–600

D. M. Brkić	453	A method for comparison of pseudo-random number generators
Hong-zhou Wang, Bao-hua Ma and Ju-sheng Shi	457	Estimation of environmental factors for the normal distribution
S. G. Chowdhury and K. B. Misra	465	Use of Demorgan's theorem in system reliability studies
K. P. Soman and K. B. Misra	469	Moments of order statistics using the orthogonal inverse expansion method and its application in reliability
P. K. Kapur, K. D. Sharma and R. B. Garg	475	Transient solutions of a software reliability model with imperfect debugging and error generation
M. N. Gopalan and D. Kar	479	Analysis of two-stage transfer-line production system subject to inter-stage inspection and arbitrary arrival and processing time distributions
I. J. Jóźwiak	483	The influence of the number of users on the reliability of a branched computer network
I. J. Jóźwiak	487	The influence of error occurrence on branched computer network reliability
K. K. Sharma and R. K. Bhutani	493	A comparison of classical and Bayes risks when the quality varies randomly
M. C. Rander, A. Kumar and R. K. Tuteja	497	Analysis of a two-unit cold standby system with imperfect assistant repairman and perfect master repairman
L. R. Goel and V. K. Tyagi	503	A two-unit cold standby system with allowed down-time and correlated failures and repairs
K. Mohandas, D. Chaudhuri and B. V. A. Rao	509	Optimal periodic replacement with inspection and minimal repair for a system which is inoperable during inspection periods
A. Srivastava	515	Performance study of *n*-MOS natural transistor fabricated by low thermal budget process
Yiu-Wing Leung	525	Reliability and cost of fault tolerant multiprocessing networks with heterogeneous nodes
M. Dohnal	539	Rough sets in reliability engineering
T. Giebel and K. Goser	545	A simple, analytical model for hot-carrier induced degradation in *n*-channel MOSFETs
M. Yamashiro, M. Satoh and Y. Yuasa	557	Comparison of MTBF in the parallel string configuration and the quad configuration systems
B. S. Dhillon and N. Yang	561	Reliability and availability analysis of warm standby systems with common-cause failures and human errors
		Technical Note
C. A. Ntuen	577	A note on determining optimum shape parameter for gamma distribution based on the number of system shocks

581 Publications, Notices, Calls for Papers, etc

583 World Abstracts on Microelectronics and Reliability

599 Corrigendum

VOLUME 32, NUMBER 5 MAY 1992 PAGES 601–754

J. Singh and B. Dayal 601 Reliability analysis of a system in a fluctuating environment

Xianhua Wei 605 Test against a change in NBUE trends with change-point unknown

Xianhua Wei 607 Test exponentiality against a monotone hazard function alternative based on TTT transformation

M. Yamashiro, M. Satoh and Y. Yuasa 611 Parallel-series and series-parallel redundant systems consisting of units having two kinds of failure rates

A. A. Chernyshev and A.G. Suchorukov 615 Physical aspects and a method for evaluating CMOS IC workability when affected by destabilizing factors

A. K. Hosni 617 Optimal smoothing parameter of Fourier series density estimates under an autoregressive dependence model

M. Triantafyllou and A. Leone 621 Electromigration reliability evaluation for a three-level metallization process

E. Haupt and H. Schäbe 633 A new model for a lifetime distribution with bathtub shaped failure rate

N. Singh 641 Representation of reliability-decay processes by time-dependent autoregressive models

Shey-Huei Sheu and Ching-Tien Liou 649 Optimal replacement of a k-out-of-n system subject to shocks

Shey-Huei Sheu 657 A general replacement of a system subject to shocks

Z. Stamenković and N. Stojadinović 663 Chip yield modeling related to photolithographic defects

K. C. Madan 669 A bulk queueing system with random failures and two phase repairs

Hong-zhou Wang, Bao-hua Ma and Ju-sheng Shi 679 Estimation of environmental factors for the log normal distribution

M. Suliman and C. A. Goben 687 Markov availability models on neural networks

Yiu-Wing Leung 699 Software reliability growth model with debugging efforts

R. O. Al-Seedy 705 The service Erlangian machine interference with balking

Hoang Pham 711 Optimal system-profit design of k-to-l-out-of-n systems

B. S. Dhillon 719 Failure modes and effects analysis—bibliography

Technical Note

D. K. Manna 733 A note on a paper by Gupta and Kumar

737 Book Reviews

After CFCs? Options for Cleaning Electronics Assemblies

Foundations for Microstrip Circuit Design

Mental Models and Human–Computer Interaction—1

Mental Models and Human–Computer Interaction—2

Reliability-Centered Maintenance: Management and Engineering Methods

Human Factors in Product Design

Network Reliability and Algebraic Structures

747 Calendar of International Conferences, Symposia, Lectures and Meetings of Interest

751 Publications, Notices, Calls for Papers, etc.

VOLUME 32, NUMBER 6 JUNE 1992 PAGES 755–900

G. C. Mishra and B. N. Pandey 755 A weighted estimator for the scale parameter of an exponential distribution

F. Guess, E. Walker and D. Gallant 759 Burn-in to improve which measure of reliability?

M. A. W. Mahmoud, M. M. Mohie El-Din and M. E. Moshref 763 Reliability of a reparable system with preventive maintenance and imperfect switch

Z. D. Prijić, S. S. Dimitrijev and N. D. Stojadinović 769 The determination of zero temperature coefficient point in CMOS transistors

L. R. Goel, P. K. Tyagi and Rakesh Gupta 775 Cost analysis of a two-unit chargeable standby system with interchangeable units and two types of failure

L. R. Goel, Rakesh Gupta and V. S. Rana 781 Stochastic analysis of a xenix operating computer system with two down modes

L. R. Goel and P. Shrivastava 793 A warm standby redundant system with correlated failures and repairs

S. E. Moafi B., L. R. Goel and Rakesh Gupta 799 A stochastic model of a system with two phases of operation

Miss Sharda and Prem Chand Garg 805 Time-dependent queueing model having heterogeneous servers

E. J. Vanderperre 811 Asymptotic behaviour of a multiple parallel system attended by a multiple repairstation

T. Hidaka 817 Approximated reliability of r-out-of-$n(F)$ system with common cause failure and maintenance

K. K. Aggarwal and Yogesh Singh 833 Ascertaining the value of reliability for a software package before release

Young Ho Chun and Chang Shin Lee 839 Optimal replacement policy for a warrantied system with imperfect preventive maintenance operations

Hoang Pham and Hanh K. Phan 845 Mean life of k-to-l-out-of-n systems with nonidentical Weibull distribution components

M. M. Alidrisi 851 The reliability of a dynamic warm standby redundant system of n components with imperfect switching

C. Constantinescu 861 Analyzing the effect of permanent, intermittent and transient faults on a gracefully degrading microcomputer

M. Dohnal 867 Reliability knowledge and fractal evaluation of chaos

J. Sztrik 875 Asymptotic analysis of a heterogeneous renewable complex system with random environments

E. A. Weis, E. Kinsbron, M. M. Snyder, B. Vogel and N. Croitoru 887 Electromigration behavior analysis of aluminum alloys thin film conductors using maximum likelihood methods

VOLUME 32, NUMBER 7 JULY 1992 PAGES 901–1050

R. K. Agnihotri, Govind Singhal and S. K. Khandelwal — 901 Stochastic analysis of a two-unit redundant system with two types of failure

V. Sridharan — 905 Optimum planned policies with minimal repair and random lead times

S. Kal — 911 Steady state and transient analysis of SFIIL

S. D. Sharma and K. S. Basati — 917 A queueing system with alternate batch service

S. A. Siddiqui and M. Subharwal — 923 The Mukherjee–Islam failure model

Yow-mow Chen, T. Fujisawa and H. Ōsawa — 925 Availability for a 2/3:G subsystem and secondary subsystem subject to shut-off rules

Hong-zhou Wang, Bao-hua Ma and Ju-sheng Shi — 931 Estimation of environmental factors for the inverse Gaussian distribution

J. C. Chan — 935 An investigation of the information contained in faulty signatures

U. Hilleringmann and K. Goser — 941 Stacked CMOS circuits integrated in laser-recrystallized silicon films

A. Csenki — 945 Sojourn times in Markov processes for power transmission dependability assessment with MatLab

R. M. Patrikar and R. Lal — 961 New method for assessing dielectric integrity of MOS oxides

D. J. Klinger — 987 Failure time and rate constant of degradation: an argument for the inverse relationship

Shey-Huei Sheu, Ching-Tien Liou and Bee-Ching Tseng — 995 Optimal ordering policies and optimal number of minimal repairs before replacement

A. Scott and T. Downs — 1003 Some observations on a software reliability model

M. Dohnal — 1015 Revitalization of primary reliability knowledge

S. O. Agbo, P. S. Neelakanta and L. M. Lay — 1029 Reliability assessment of CCDs operating under ionizing radiation ambients: failure–simulation studies via electrical overstressing

H. Reiche — 1043 Society of Reliability Engineers Bulletin

1045 Book Reviews
Assurance Technologies, Principles and Practices
Reliability by Design. CAE Techniques for Electronic Components and Systems

1049 Publications, Notices, Calls for Papers, etc.

VOLUME 32, NUMBER 8 AUG 1992 PAGES 1051–1198

E. J. Vanderperre — 1051 Reliability of a space shuttle subject to space erosion

Yow-mow Chen, T. Fujisawa and H. Ōsawa — 1053 Availability and reliability of the system with pre-emptive priorities and shut-off rules

H.-B. Bemmann — 1063 Application of the hierarchical fault model to reliability considerations

M. A. Aziz, M. A. Sobhan and M. A. Samad — 1067 Reduction of computations in enumeration of terminal and multiterminal pathsets by the method of indexing

S. D. Sharma and K. S. Basati — 1073 Stochastic model of k-parallel service channels

V. Sridharan — 1079 Cost analysis for two-unit warm standby systems

R. P. Kaushal, N. Chammas and H. Singh	1083	A new formulation for state equation representation for Petri nets
G. S. Mokaddis, S. W. Labib and E. A. Soliman	1091	The analysis of a three-phase queueing servicing system with renewable servers
Shey-Huei Sheu and Ching-Tien Liou	1105	An ordering policy with age-dependent minimal repair and age-dependent random repair costs
B. S. Dhillon	1115	Reliability testing: bibliography
B. S. Dhillon and O. C. Anude	1137	Mining equipment reliability: a review
M. Dohnal	1157	Ignorance and uncertainty in reliability reasoning
K.-H. Wang and B. D. Sivazlian	1171	Cost analysis of the M/M/R machine repair problem with spares operating under variable service rates
F. Beichelt	1185	A general maintenance model and its application to repair limit replacement policies
	1197	Society of Reliability Engineers Bulletin

VOLUME 32, NUMBER 9 SEPT 1992 PAGES 1199–1348

M. C. Rander, A. Kumar and R. K. Tuteja	1199	A two-unit cold standby system with major and minor failures and preparation time in the case of major failure
R. T. Arora and R. K. Tuteja	1205	Stochastic analysis of an Erlangian arrival with linear cost structure
Gang Soo Lee and Jung-mo Yoon	1215	An empirical study on complexity metrics of Petri nets
V. Jayabalan and D. Chaudhuri	1223	Sequential imperfect preventative maintenance policies: a case study
J. M. Kontoleon	1231	The reliability modelling of RAM/ROM fault tolerant memories
Tongde Guo and Jinhua Cao	1237	Reliability analysis of a two-unit redundant system with a replaceable repair facility
D. Badenius	1241	Note on MTBF versus mean-wear-life versus Mil-Hdbk-217
L. R. Goel and Preeti Shrivastava	1243	Reliability analysis and redundancy optimisation of a multimodular fault tolerant system
M. O. Abou El-Ata	1251	An interarrival hyperexponential machine interference with balking and reneging
Yow-mow Chen, T. Fujisawa and H. Ōsawa	1257	Availability for $2/n:F$ and secondary subsystems with general repair-time distributions and shut-off rules
Ravindra K. Tyagi, S. Kumar, R. C. Tiwari and S. K. Bhattacharaya	1271	Parametric empirical Bayes approach to reliability analysis for the geometric life model
Shey-Huei Sheu and Ching-Tien Liou	1283	An age replacement policy with minimal repair and general random repair cost
V. C. Prasad, V. Sankar and K. S. Prakasa Rao	1291	Generation of vertex and edge cutsets
V. Ramachandran, V. Sankaranarayanan and S. Seshasayee	1311	Fuzzy reliability modelling—linguistic approach
Xianhua Wei	1319	Relative mean residual life: theory and related topics
	1327	Calendar of International Conferences, Symposia, Lectures and Meetings of Interest
	1331	World Abstracts on Microelectronics and Reliability

VOLUME 32, NUMBER 10 OCT 1992 PAGES 1349–1496

J. H. Huang	1349	A study of failure of SMT solder joints under thermal cycles by statistics
R. K. Tuteja and G. Taneja	1353	Cost–benefit analysis of a two-server, two-unit, warm standby system with different types of failure
L. R. Goel and P. Shrivastava	1361	Transient analysis of a multiple-unit redundant system
L. R. Goel and V. K. Tyagi	1367	A two unit priority redundant system with three modes and correlated failures and repairs
Lien Zhao-Tung	1373	Reliability analysis of a repairable system in a randomly changing environment
J. C. Chan and B. F. Womack	1379	On the relation of errors and its syndrome in signature analysis
S. A. Salem	1385	Bayesian estimation of a non-linear failure rate from censored samples type II
M. O. Abou-El-Ata and A. I. Shawky	1389	The single-server Markovian overflow queue with balking, reneging and an additional server for longer queues
Who Kee Chung	1395	A reliability analysis of a *k*-out-of-*N*:G redundant system with the presence of chance common-cause shock failures
H. H. Liu, W. T. Yang and C. C. Liu	1401	An improved Boolean algebra method for computing the network reliability
O. Martynenko	1421	Some possibilities of restoration organization selection for complex radioelectronic systems
R. K. Agnihotri, G. Singhal and S. K. Khandelwal	1431	Two-unit redundant system with random shocks and inspection
S. K. Singh, R. P. Singh and R. B. Singh	1443	MTTF and availability evaluation of a two unit, three state redundant system with a proviso of random activation
S. A. Siddiqui, Balkrishan, S. Gupta and M. Subharwal	1453	A finite range failure model
Dilip Roy and R. P. Gupta	1459	Classifications of discrete lives
		Technical Notes
T. S. Uma Maheswari, A. Rekha and A. C. N. Raghava Char	1475	Reliability of single strength under *n*-stresses
K. K. Sharma and R. K. Bhutani	1479	Non-parametric estimation of sample size and censoring time in life testing experiments
R. Bhandari	1483	On distribution of cycles in a Markovian queueing system
	1489	Book Reviews *What Every Engineer Should Know About Microcomputers Hardware/Software Design—A Step-by-Step Example* *Process Improvement in the Electronics Industry* *Contamination Effects on Electronic Products*
	1493	Publications, Notices, Calls for Papers, etc.

VOLUME 32, NUMBER 11 NOV 1992 PAGES 1497–1656

RELIABILITY PHYSICS OF ADVANCED ELECTRON DEVICES

N. Stojadinović	1497	Editorial
W. H. Krautschneider, H. Terletzki and Qin Wang	1499	Reliability problems of submicron MOS transistors and circuits

J. A. Segura, J. Figueras and A. Rubio	1509	Approach to the analysis of gate oxide shorts in CMOS digital circuits
C. Bergonzoni, G. Dalla Libera, R. Benecchi and A. Nannini	1515	Dynamic hot carrier degradation effects in CMOS submicron transistors
K. P. Rodbell	1521	Electromigration behavior of multilayered Al/Hf and Al/Ti fine lines and its dependence on Cu and Pd solute additions
J. S. Suehle and H. A. Schafft	1527	Techniques and characterization of pulsed electromigration at the wafer-level
H. Kitagawa, S. Murata, J. Nagai, S. Kuroda, M. Amagai, Y. Imamura, M. Itoh and S. Hasegawa	1533	Single bit failure mechanism in DRAMs caused by MILO cracks
F. Corsi, S. Martino, C. Marzocca, R. Tangorra, C. Baroni and M. Buraschi	1539	Critical areas for finite length conductors
N. Maene, J. Vandenbroeck and K. Allaert	1545	On-chip electrostatic discharge protections in advanced CMOS technologies
S. Graffi, Zs. M. V.-Kovács, G. Masetti and D. Golzio	1551	EMI-induced failures in integrated circuit operational amplifiers
F. Fantini and F. Magistrali	1559	Reliability of compound semiconductor devices
A. Konttinen and J. Leino	1571	Long term degradation of GaAs integrated circuits
P. C. Conti, L. Marchisio and G. Clerico Titinet	1577	Performances and reliability of HEMTs: state of the art and experimental analysis
B. Kovács, R. Veresegyházy, I. Mojzes, K. Kazi, F. Csányi, I. Szűcs, A. Sonkoly, I. Házman, I. Deák, I. Menyhárt and Z. Horváth	1585	An advanced MESFET burn-in method and equipment
K. Nikawa	1589	VLSI failure analysis: a review
G. A. Azzini, G. Arman and P. Montangero	1599	The scanning optical microscope: a powerful tool for failure analysis of electronic devices
B. Picart and S. Diez Minguez	1605	Test method in voltage contrast mode using liquid crystals
D. Conard, J. D. Russell, J. Laurent, A. Skaf and B. Courtois	1615	Multiple adjacent image processing for automated failure location using electron beam testing
F. Grabowski and E. Stolarski	1621	A complementarity of the $1/f$ noise and the charge-pumping methods for determination of the degradation of the small size MOS transistors
A. Diligenti, B. Neri and R. Saletti	1627	Low-frequency noise measurements as a complementary tool in the investigation of integrated circuit reliability
A. Bossche	1633	On-chip stress, metal deformation and moisture measurements
A. Motta and R. Gussoni	1639	Reliability monitoring of components for telecom applications: failure mechanisms driving technology assessment
J. Y. Boulaire, J.-P. Mercier, C. Patrac and D. Riviere	1645	Technological analysis of integrated circuits as a part of a manufacturing lines agreement for France Telecom: methodology and examples of potential reliability problems
T. I. Băjenescu	1651	New aspects of the reliability of lithium thyonil chloride cells
	1655	Publications, Notices, Calls for Papers, etc.

VOLUME 32, NUMBER 12 DEC 1992 PAGES 1657–1800

S. D. Sharma and Satya Bhushan	1657	On a stochastic model of a non-Markovian time-dependent queueing system with general intertransition time distribution
Y. V. S. Sarma	1663	A $G\|M\|M$ system with $M\|M$ switch and orientation time for the repair facility
A. H. El-Mawaziny	1667	Exact fiducial bounds for the reliability of series systems with components having exponential time to failure distributions
M. N. Gopalan, K. S. Bhanu and N. N. Murulidhar	1675	Cost analysis of a two-unit repairable system subject to on-line preventive maintenance and/or repair
M. N. Gopalan and S. V. Simhan	1681	Analysis of monitoring policies
L. R. Goel and P. Shrivastava	1687	A two-unit standby system with imperfect switch, preventive maintenance and correlated failures and repairs
M. O. Abou El-Ata and K. A. M. Kotb	1693	A linearly dependent service rate for the queue: $M/M/1/N$ with general balk function, reflecting barrier, reneging and an additional server for longer queues
B. S. Dhillon and N. Yang	1699	Stochastic analysis of standby systems with common-cause failures and human errors
R. Gupta and A. Chaudhary	1713	A two-unit priority standby system subject to random shocks and Releigh failure-time distribution
H. Ratschek and J. Rokne	1725	The transistor modeling problem again
S. S. Elias and M. Y. Haggag	1741	Availability, MTTF and cost analysis of a three-state parallel redundant multi-component system under critical human failures
S. Yamada, J. Hishitani and S. Osaka	1763	Software reliability measurement and assessment based on non-homogeneous Poisson process models: a survey
	1775	Book Reviews *Software Reliability Handbook* *Assembling and Troubleshooting Microcomputers* *Electronic Equipment Packaging Technology*
Hans Reiche	1779	Society of Reliability Engineers Bulletin
	1781	World Abstracts on Microelectronics and Reliability
	i	Title Section, Volume, Contents and Author Index, Volume 32, 1992

Reproduced with the permission of Pergamon Press Inc., by University Microfilms Inc. Duplication or resale without permission is prohibited.